# X-ray diffraction set-up & data processing

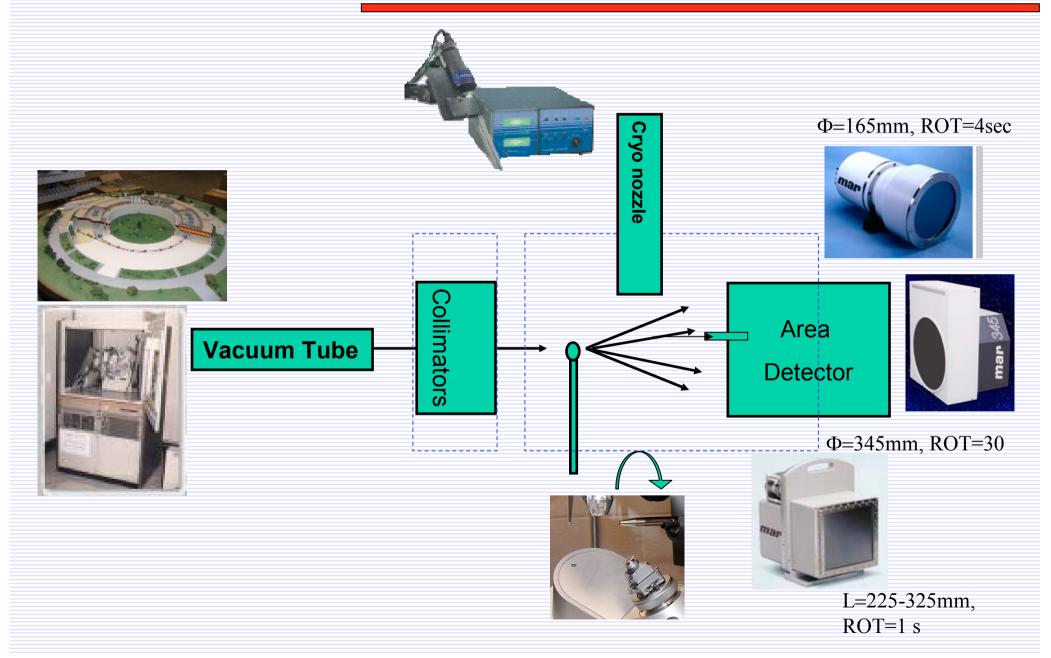
Maurizio Polentarutti

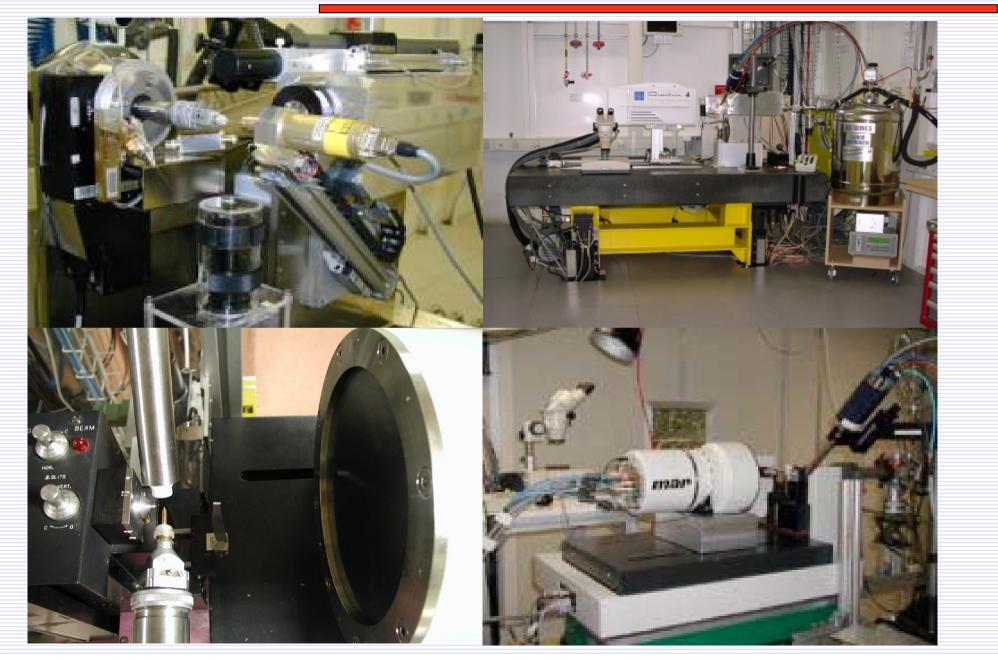
Elettra, XRD1 beamline

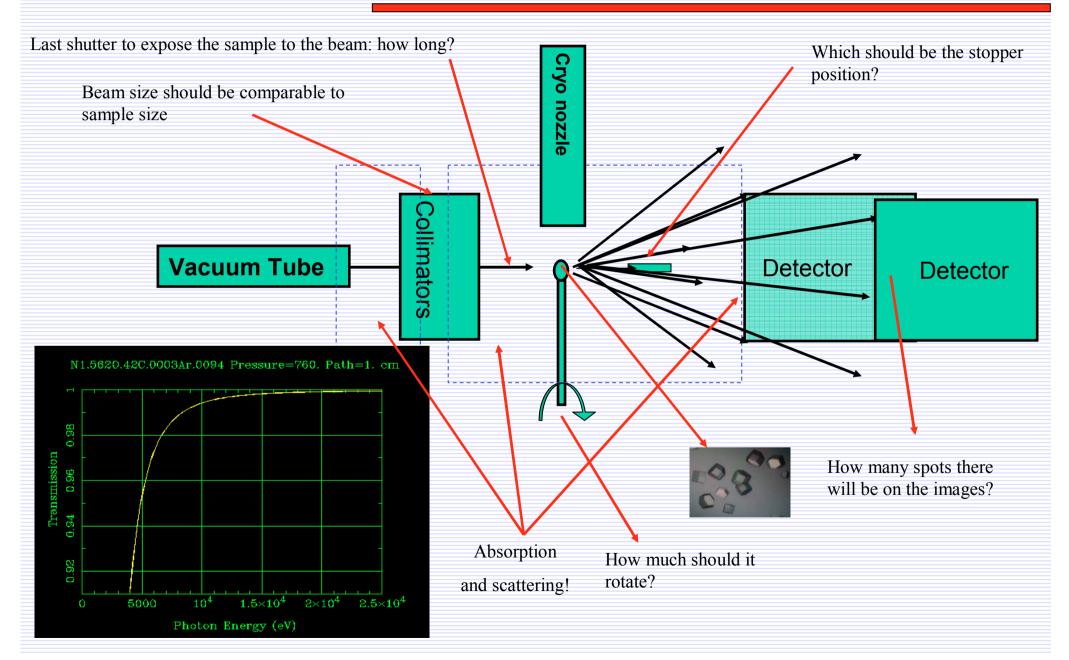
- Common to all the PX beamlines and *home* labs
- Main components (in order of appearance):
  - Slits (beam shapers)
  - Sample (protein single crystal)
  - Sample cooler system
  - Sample manipulator system (horizontal spindle axis)
  - Fluorescence detection system
  - (Primary)-Beam stopper
  - Detector
- Experimental key parameters

Sample-to-detector distance, wavelength, detector surface, beam stopper position, sample external and unit-cell dimensions, sample orientation, detector angular position.

• Small differences....







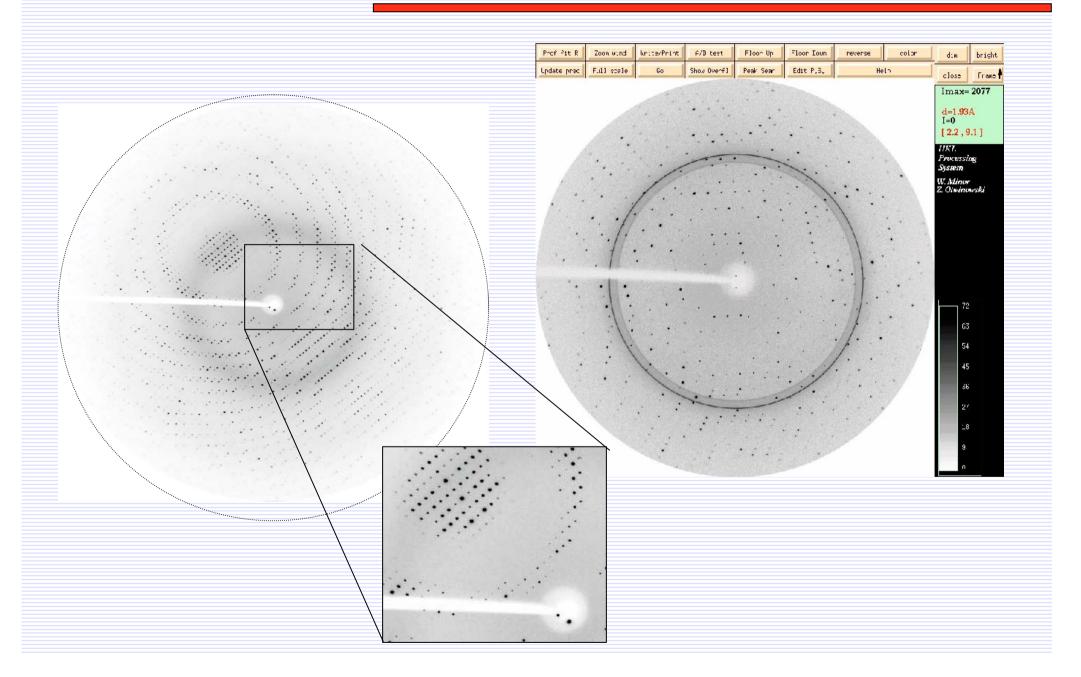
Why do we want to know the diffracted-beams intensities?

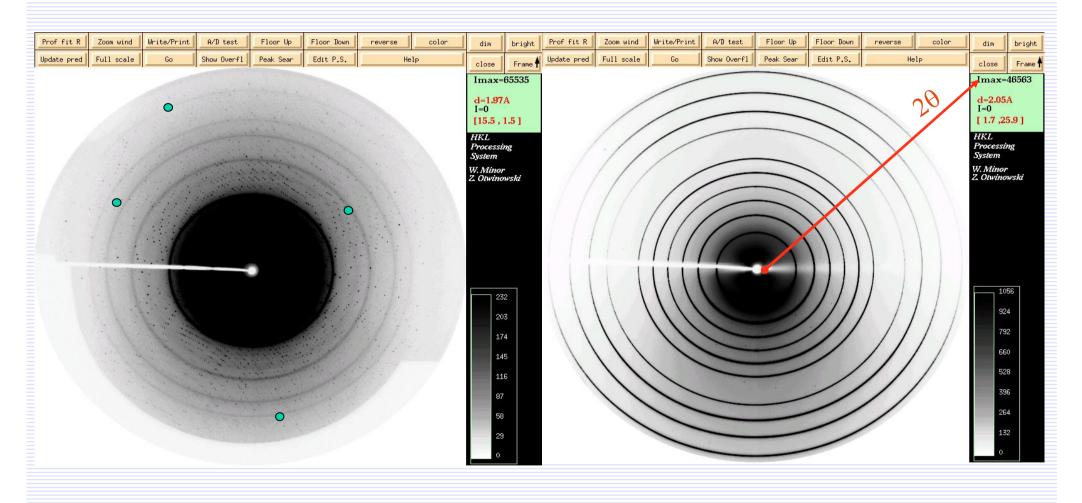
1. The electron density equation:

$$\rho(x, y, z) = \frac{1}{V_c} \sum_{h} \sum_{k} \sum_{l} |F(h, k, l)| \cdot e^{-2\pi i (hx + ky + lz) + i\alpha (h, k, l)}$$

2. The integrated intensity for the reflection (h k l):

$$I(\text{int, h k l}) = \frac{\lambda^3}{\omega \cdot V_{\text{cell}}^2} \times \left(\frac{e^2}{\text{mc}^2}\right)^2 \times V_{\text{cr}} \times I_0 \times L \times P \times A \times |F(\text{hkl})|^2$$





Protein (and bad cryosolution)

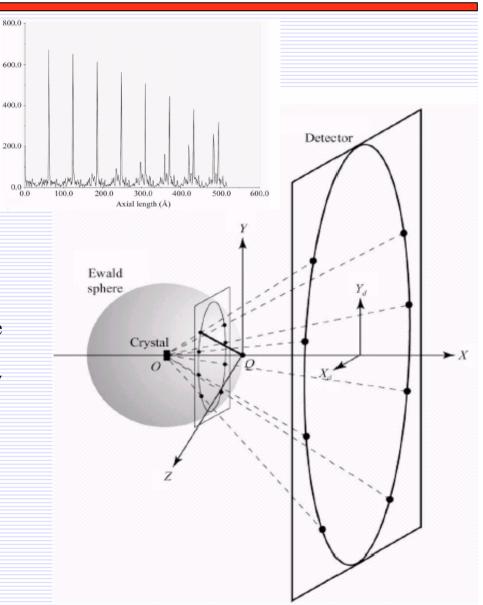
LaB<sub>6</sub> – policristalline powder in capillary ( not well-centered)

### How the integration works:

If the members of a set of reciprocal-lattice planes perpendicular to a chosen direction t are well separated, then the projections of the reciprocal-lattice vectors onto **t** will have an easily recognizable periodic distribution.

About 7300 separate roughly equally spaced directions. For each direction **t**, the distribution of the corresponding F(k)coefficients is surveyed to locate the largest local maximum. The and 'values associated with the 30 largest maxima are selected for refinement by a local search procedure to obtain an accuracy of 10-4 rad ( 0.006 ).

Directions are chosen from these vectors to give a linarly independent set of three basis vectors of a primitive real-space unit cell. These are then converted to the basis vectors of the reciprocal cell. The resultant unit cell is then reduced and analyzed in terms of the 44 lattice types (Burzlaff et al., 1992).



# Optimization of Data Collection

- Pre-process at least one image (preferably two at 90° to each other) to obtain:
  - Cell parameters, crystal orientation and putative Laue group
- Estimate of mosaicity
- Effective resolution limit
  - Crystal to detector distance
  - Exposure time
- Strategy for data collection
- Remember!
  - This is the last experimental stage if you collect bad data now you are stuck with it.
  - No data processing program can rescue the irredeemable!

# What is needed prior to running *Mosflm*?

- X-ray images
- Experimental details (e.g. detector type, direct beam position, wavelength, etc)
- The program itself and a computer to run it on!

(Q)QOPEN: file opened on unit 1 Status: READONLY
<B><FONT COLOR="#FF0000"><!--SUMMARY\_BEGIN-->
Logical Name: muldlx1\_301.mar2000 Filename: muldlx1\_301.mar2000
<!--SUMMARY\_END--></FONT></B>

Crystal to detector distance of 250.00mm taken from image header

Wavelength of 1.54180A taken from image header

Crystal to detector distance of 250.00mm taken from image header

Wavelength of 1.54180A taken from image header

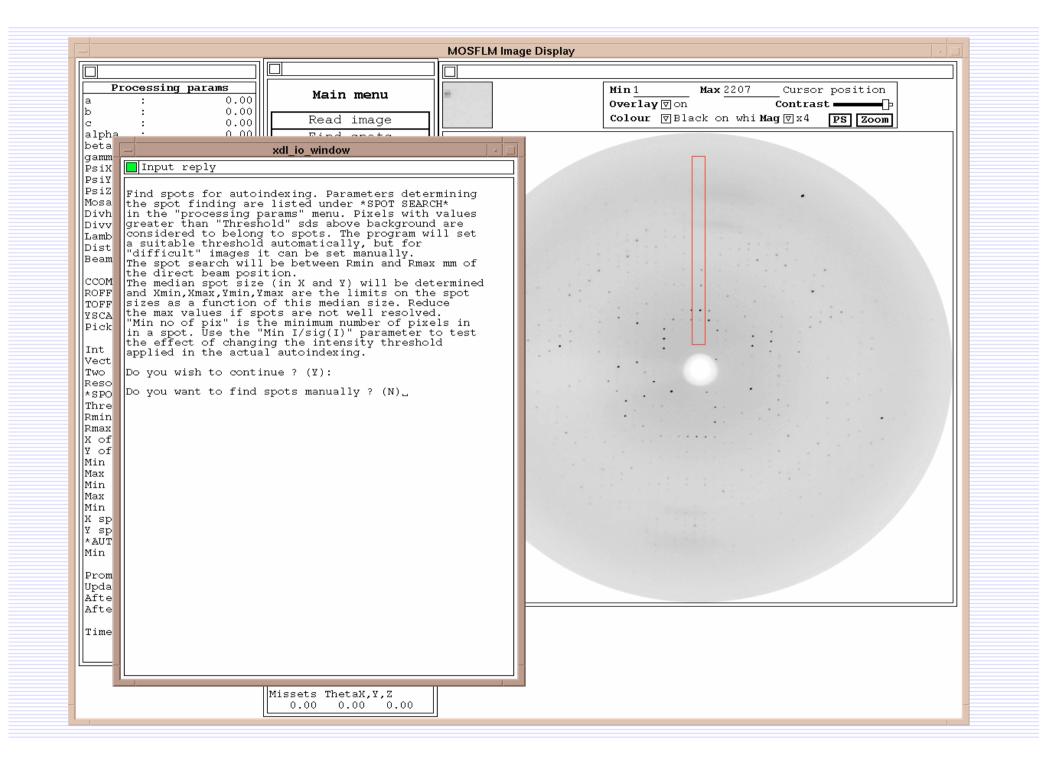
Pixel size of 0.1500mm taken from image header.

Start and end phi values for image 1 from image header are 279.00 and 280.00 degrees. image FILENAME: muldlx1\_301.mar2000

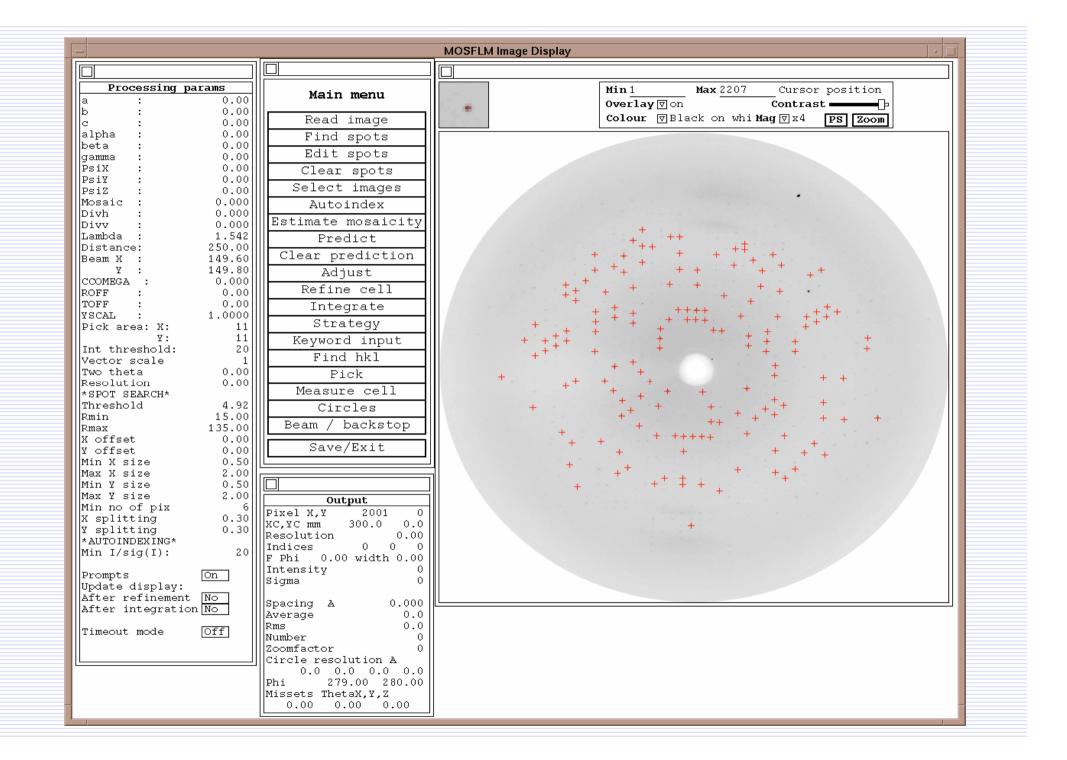
(Q)QOPEN: file opened on unit 1 Status: READONLY
<B><FONT COLOR="#FF0000"><!--SUMMARY\_BEGIN-->
Logical Name: muldlx1\_301.mar2000 Filename: muldlx1\_301.mar2000
<!--SUMMARY END--></FONT></B>

The red circle denotes the region behind the backstop shadow (Use BACKSTOP keyword to set this.)

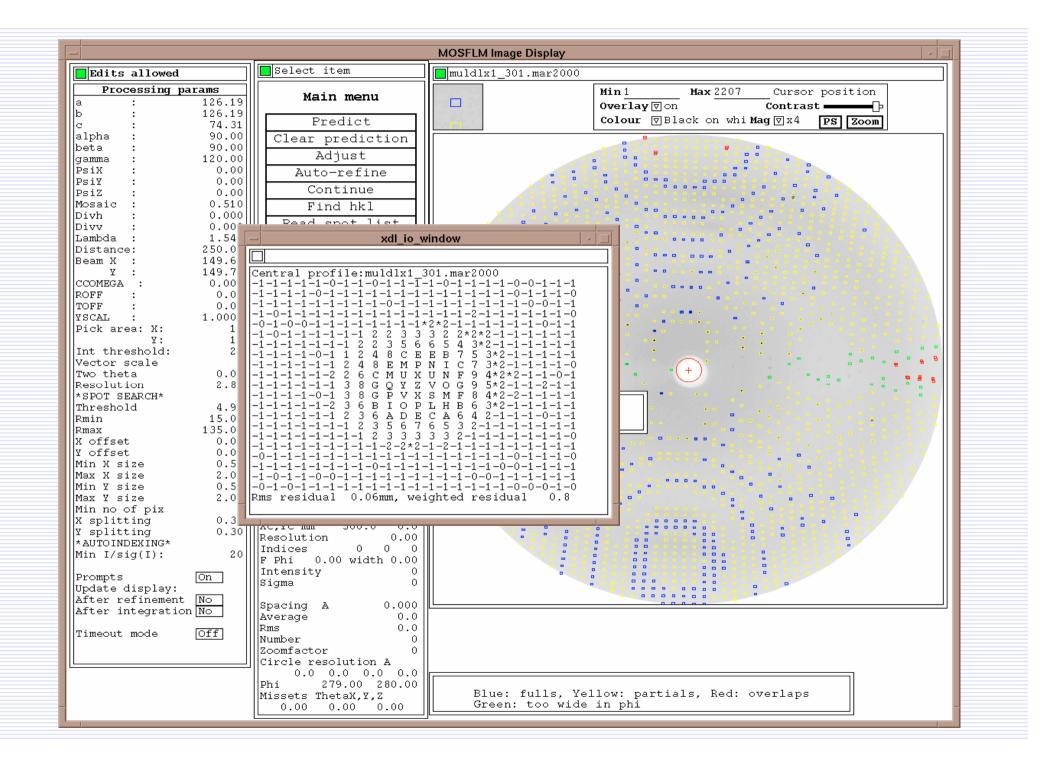
MOSFLM Image Display			
Edits allowed	Select item	muldlx1_301.mar2000	
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b : 0.00 c : 0.00	Read image	Colour VBlack on whi Mag VX4 PS Zoom	
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gamma : 0.00	Edit spots		
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PsiZ : 0.00	Select images		
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Divv : 0.000	Estimate mosaicity		
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Y: 11 Int threshold: 20	Keyword input		
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*SPOT SEARCH* Threshold 5.00	Measure cell		
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Y offset 0.00			
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Min Y size 0.50			
Max Y size 2.00 Min no of pix 6	Output		
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Y splitting 0.30 *AUTOINDEXING*	Resolution 0.00 Indices 0 0 0		
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After integration No	Spacing A 0.000 Average 0.0		
Timeout mode Off	Rms 0.0		
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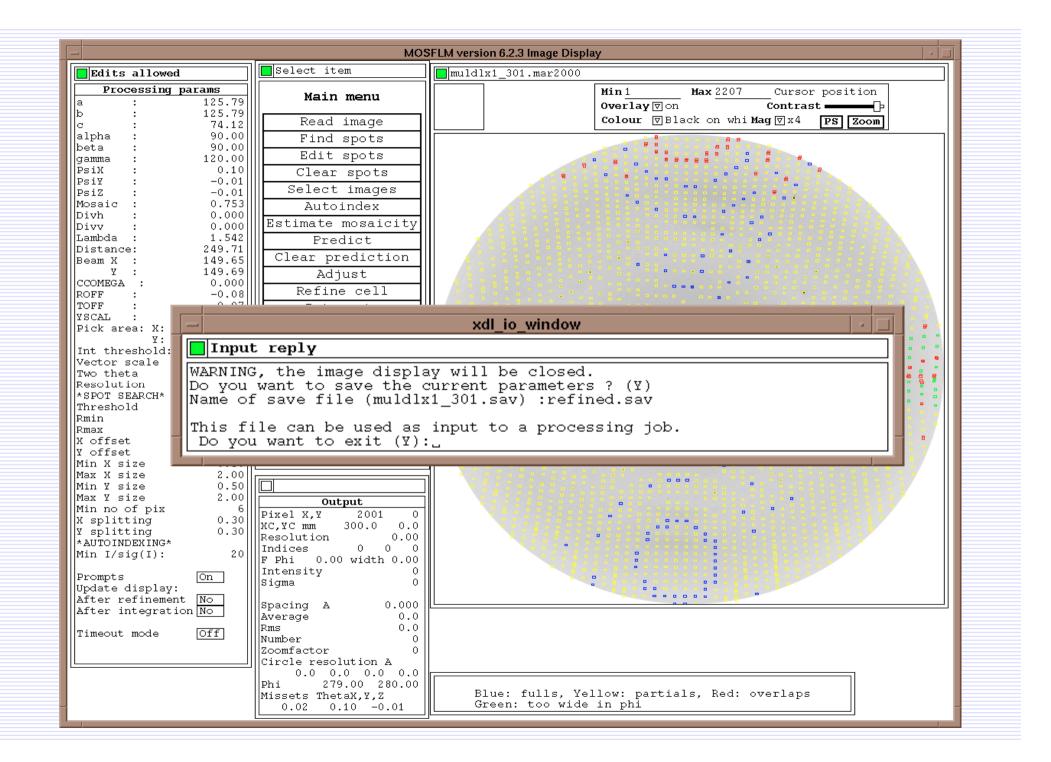


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- MOSFLM Image Display				
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	Circle resolution A			
	0.0 0.0 0.0 0.0			
	Phi 279.00 280.00 Missets ThetaX,Y,Z	Blue: fulls, Yellow: partials, Red: overlaps		
	0.00 0.00 0.00	Green: too wide in phi		





# Scaling and merging with "Scala"

- scaling and merging is the most important diagnostic step in terms of data quality.
- it is important that it be performed as soon as possible after data collection and preferably during.
- in many cases it is a straightforward procedure but can become complicated. An understanding of the underlying principles is important.
- sources of systematic errors
- parameterization of scaling
- estimates of data quality
- estimation of standard errors
- outlier rejection

# Steps in scaling

- Choose scaling model
  - Should reflect the experiment
    - X-ray source intensity variation
    - Changes in diffracting volume
    - Sample or air absorption
    - Radiation damage
- Analyze results
  - Should the sample be discarded?
  - What is the useful resolution?
  - Are there outliers or bad images?
  - What is the spacegroup?

# Factors affecting scale

- Incident beam
  - intensity
  - size
  - primary beam absorption
- Sample
  - diffracting volume
  - diffracted beam absorption

- Detector
  - calibration
  - time stability
  - bad pixels

#### Miscellaneous

beam stop and cryo-stream shadows

# Incident beam related factors

- Synchrotron
  - smooth decay of beam intensity
  - any discontinuities (e.g. beam injection) should be noted and included in scaling model
  - illuminated volume
  - shutter synchronization/goniometer rotation speed

# Crystal related factors

- Sample absorption
  - diffracted beam absorption (shape dependent)
  - important for weak anomalous signal
- Radiation damage
  - can be significant on high brilliance sources
  - difficult to correct for
  - modeled as change in relative B-factor
  - extrapolation to zero dose

## Detector related factors

#### calibration errors

- spatial distortion
- non-uniformity of response
- time stability
- bad pixels

# Miscellaneous factors

- unavoidable
  - zingers
- avoidable
  - beam stop shadow
  - cryo-stream shadow
  - should be dealt with at integration stage

### Determination of scale factors

What information do we have?

Scales are determined by comparison of symmetry-related reflections, i.e. by adjusting scale factors to get the best internal consistency of intensities. Note that we do not know the true intensities and an internally-consistent dataset is not necessarily correct. Systematic errors will remain

Minimize  $\Delta \Phi = \Sigma_{hl} w_{hl} (I_{hl} - 1/k_{hl} < I_h >)^2$ 

$$\begin{split} I_{hl} \text{ l'th intensity observation of reflection } \mathbf{h} \\ k_{hl} \text{ scale factor for } I_{hl} \qquad < I_h > \text{ current estimate of } I_h \\ g_{hl} &= 1/k_{hl} \text{ is a function of the parameters of the scaling model} \end{split}$$

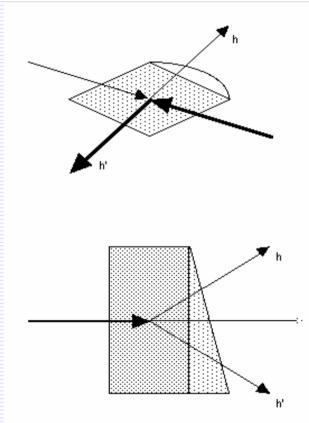
 $g_{hl} = g($  rotation/image number) . g(time) . g(s)

... other factors

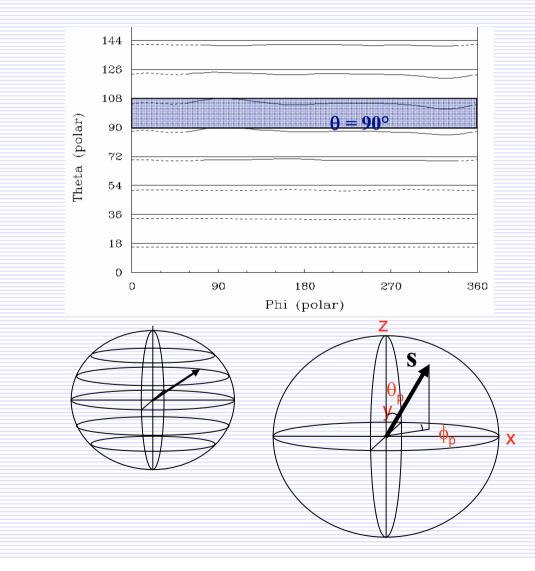
Primary beam  $s_0$  B-factor Absorption

## Absorption correction

- serious for longer wavelengths and larger irregular samples
- we typically do not have enough data to find true absorption corrections
- good corrections require data recorded with sample in multiple orientations
- some strategies can minimize effect of absorption on quality of observed anomalous differences
- inverse beam
- simultaneous measurement of I+ & I-



## Spherical harmonics



$$A(\mathbf{s}) = \Sigma_{\text{Im}} \mathbf{c}_{\text{Im}} \mathbf{Y}_{\text{Im}}(\theta_{p}, \phi_{p})$$

- linear coefficients clm determined as parameters.
- Note the surface is not centrosymmetric (see e.g. equator  $\theta = 90^{\circ}$ )
- i.e. different corrections are applied to I+ & I-
- Graph along lines of latitude
- Dashed lines where there is no data

## How well are the scales determined?

- Note that determination of scaling parameters depends on symmetry-related observations having **different** scales. If all observations of a reflection have the same value of the scale component, then there is no information about that component and it remain as a systematic error in the merged data (this may well be the case for absorption for instance)
- Thus to get intensities with the lowest absolute error, the symmetry-related observations should be measured in as different way as possible (eg rotation about multiple axes). This will increase Rmerge, but improve the estimate of <I>.
- ٠
- Conversely, to measure the most accurate differences for phasing (anomalous or dispersive), observations should be measured in as similar way as possible

# Results of scaling: R-factors

#### • Data quality indicators:

Rmerge (Rsym) =  $\Sigma$  | Ihl -  $\langle Ih \rangle$  |  $\langle Ih \rangle$  |

This is the traditional measure of agreement, but it increases with higher multiplicity even though the merged data is better

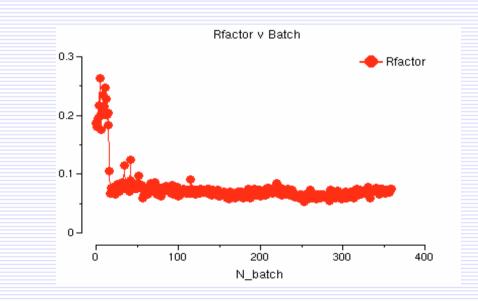
#### • Diffraction intensities values

• Corrected  $\sigma(I)$  is compared with the intensities: the most useful statistic is  $\langle I \rangle / \sigma(\langle I \rangle) \rangle$  (labelled Mn(I)/sd in tables)

# Results of scaling: Common sense checks

#### <u>Are some parts of the data bad?</u>

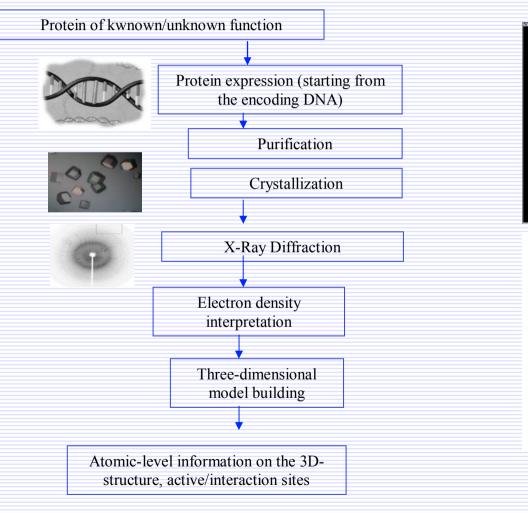
• Analysis of Rmerge against batch number gives a very clear indication of problems local to some regions of the data. Perhaps something has gone wrong with the integration step, or there are some bad images

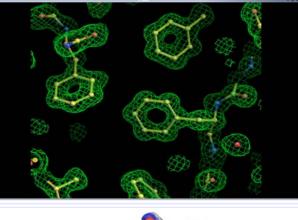


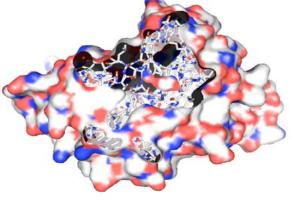
• Here the beginning of the dataset is wrong due to problems in integration (e.g. poor orientation matrix in MOSFLM at start of job.)

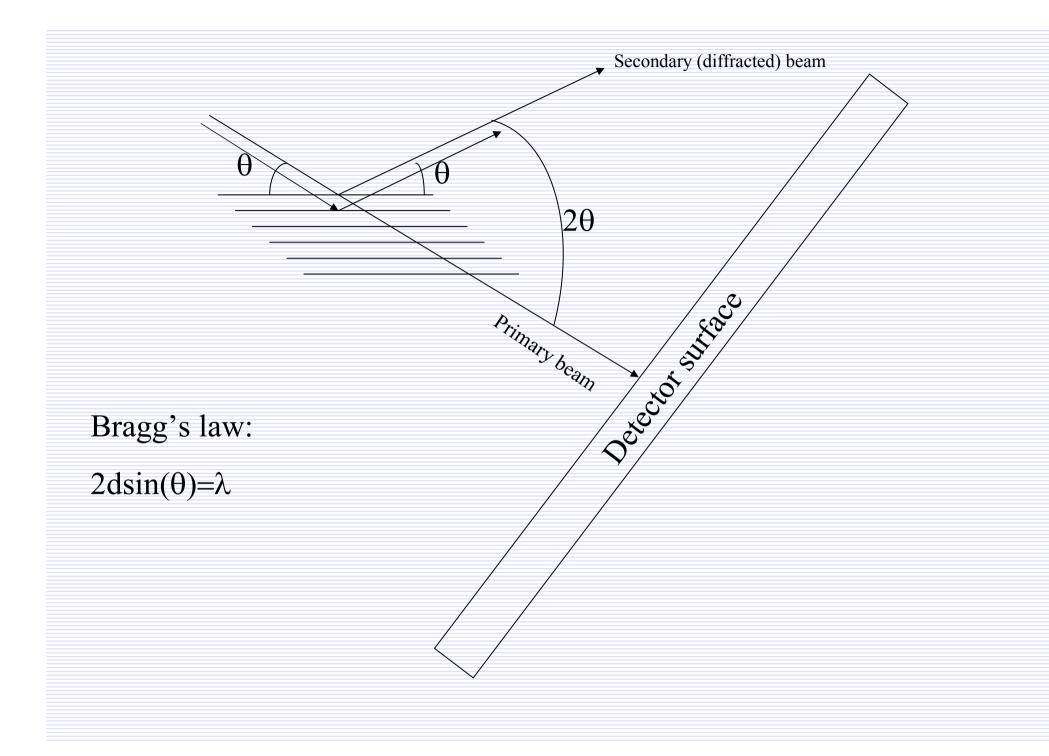
Now we have the |F(hkl): what's missing?

$$D(x, y, z) = \frac{1}{V_{c}} \sum_{h} \sum_{k} \sum_{l} |F(h, k, l)| \cdot e^{-2\pi i (hx + ky + lz) + i\alpha (h, k, l)}$$









### Spots: Full/ partials

